

Search Notes

Application/Control No.

10/605,650

Examiner

Brian E. Miller

Applicant(s)/Patent under
Reexamination

CHANG, YEN-JEN

Art Unit

2627

SEARCHED

Class	Subclass	Date	Examiner
720	692 694	10/12/2006	BEM
720	698 688	10/12/2006	BEM

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search (enclosed)	10/12/2006	BEM
PLUS Search	10/13/2006	BEM